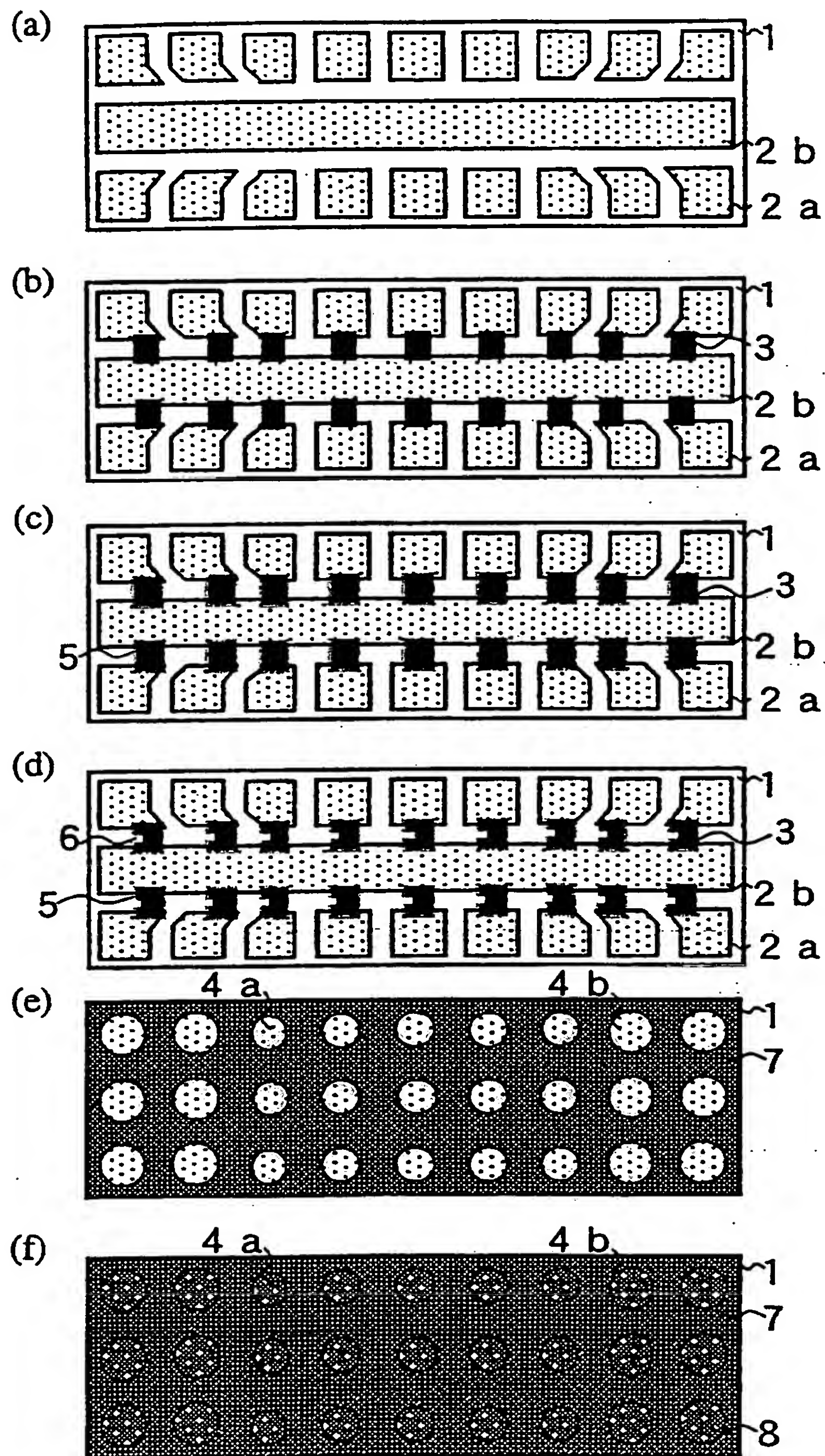


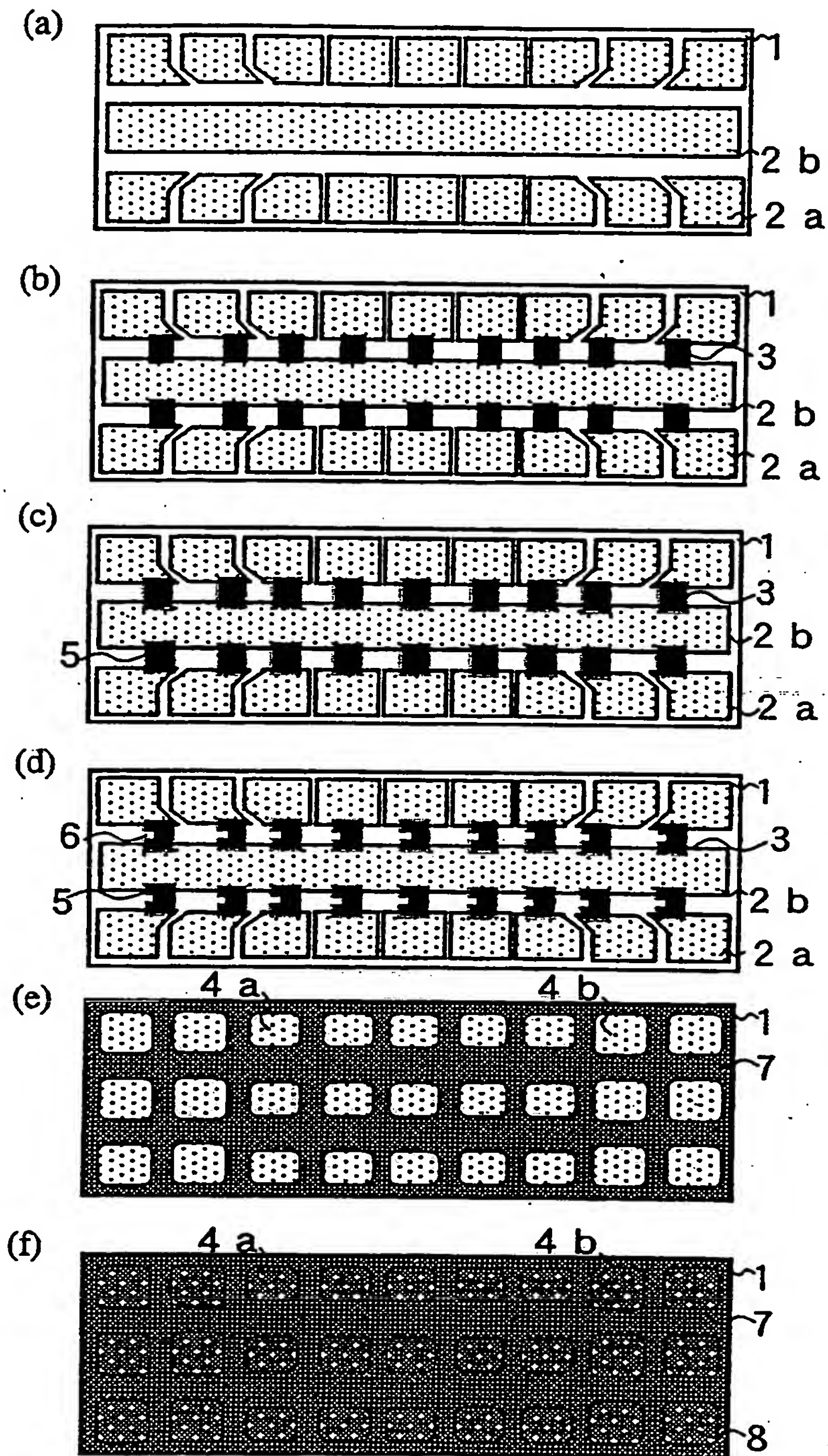
Figure 1 consists of two plan views, (a) and (b), of semiconductor devices. Both views show a central horizontal region (2b) and two side regions (2a) connected by vertical bridges (4a). The top and bottom regions are labeled 1 and 3. The labels 4a, 4b, 2a, 2b, 1, and 3 are used to identify specific components.

Figure 1 consists of two schematic diagrams, (a) and (b), illustrating different photomask patterns. Both diagrams show a central horizontal band (2b) and side bands (2a) connected by vertical bars (3). The patterns are defined by regions 1, 2a, 2b, 3, and 4a/4b. In diagram (a), the side bands (2a) are connected to the central band (2b) by vertical bars (3) that are wider than the side bands. In diagram (b), the side bands (2a) are connected to the central band (2b) by vertical bars (3) that are narrower than the side bands.

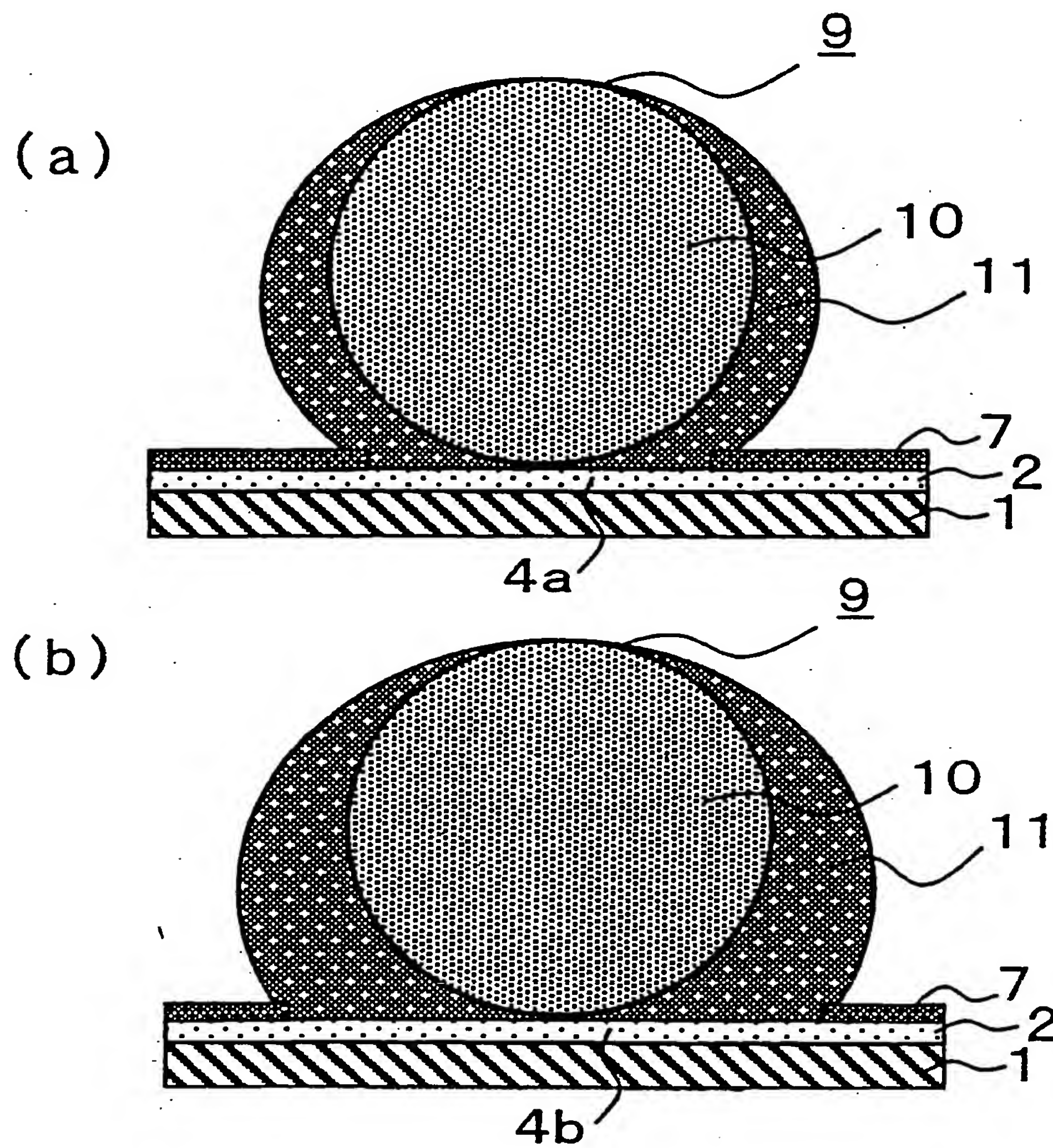
[Fig. 3]



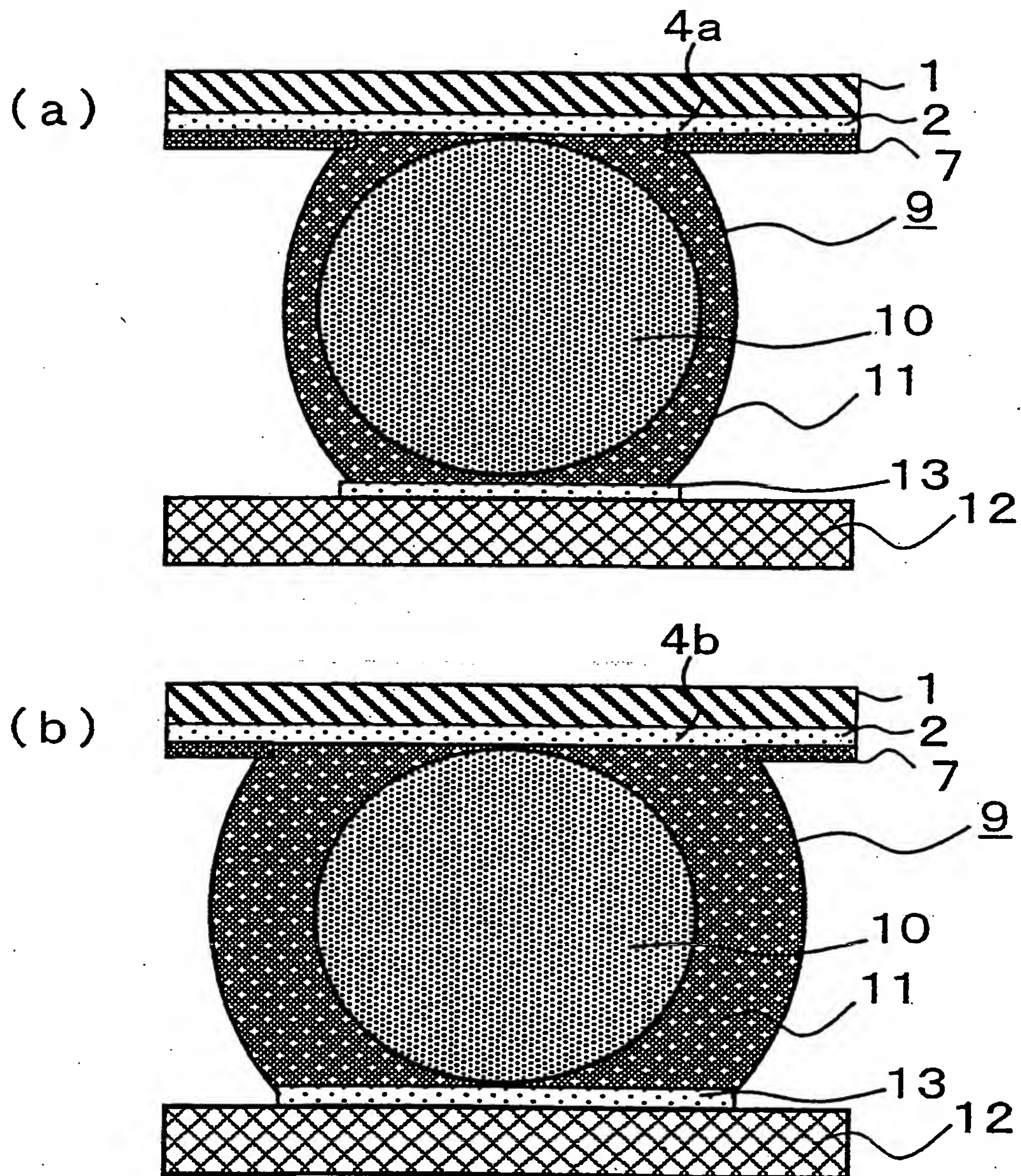
[Fig. 4]



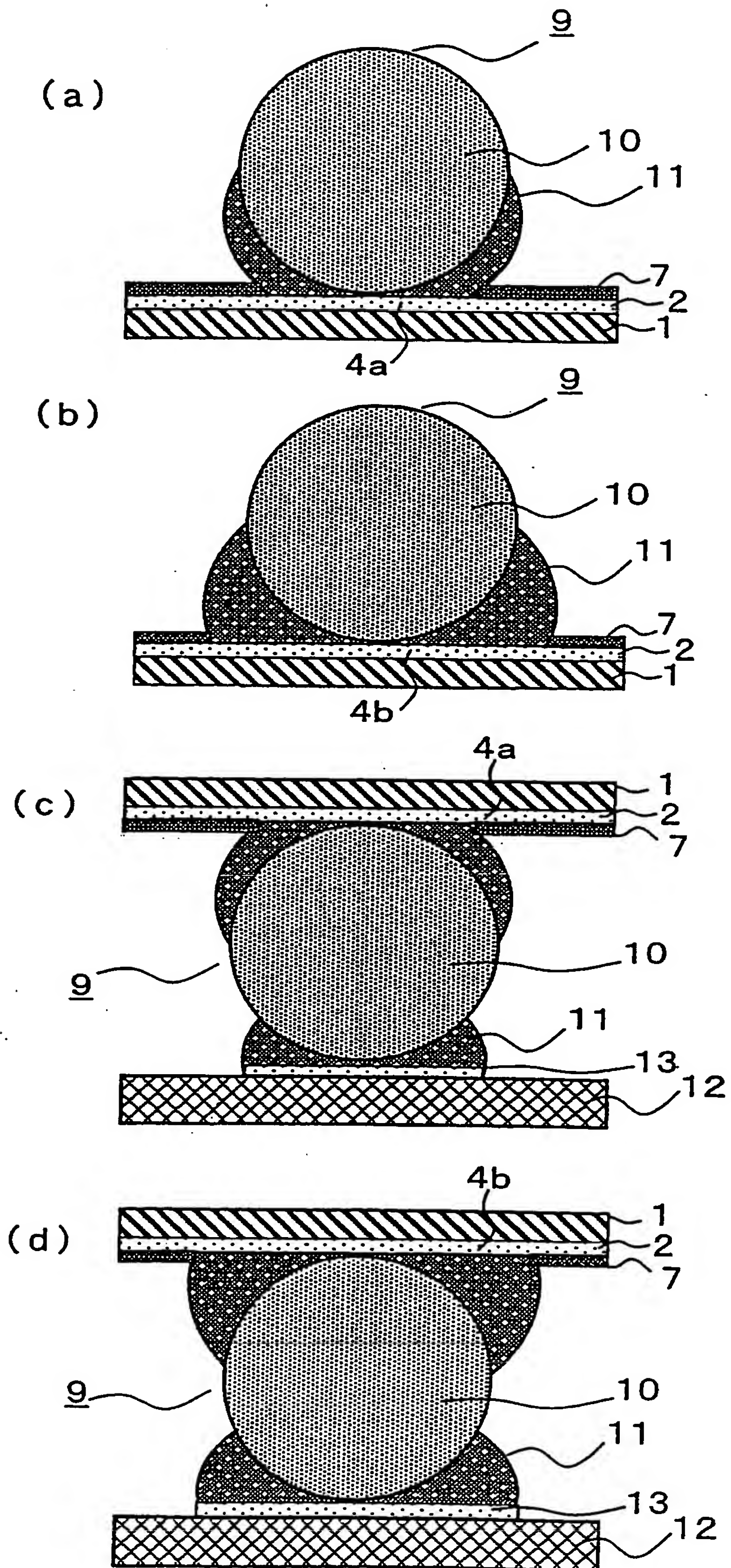
[Fig. 5]



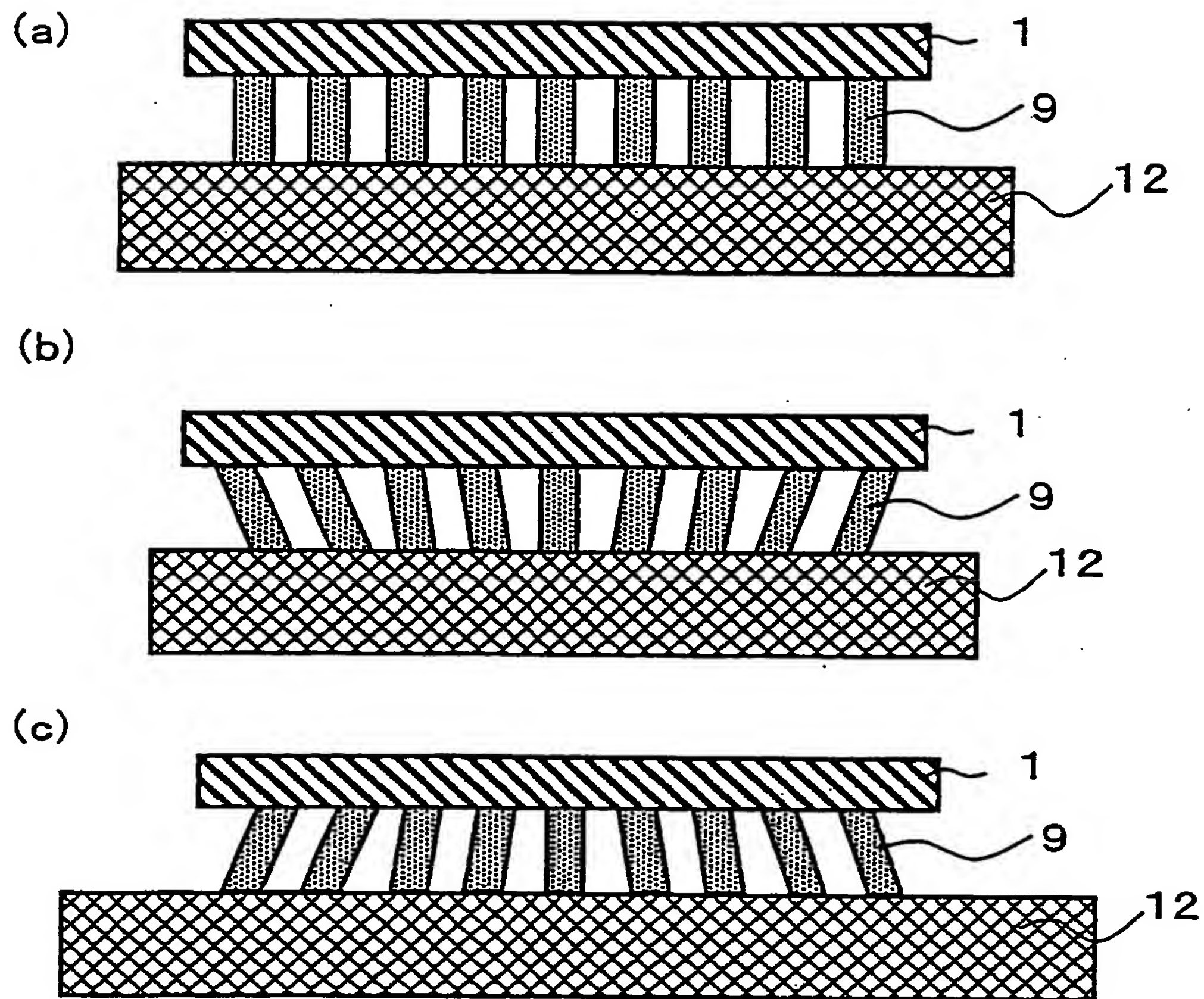
[Fig. 6]



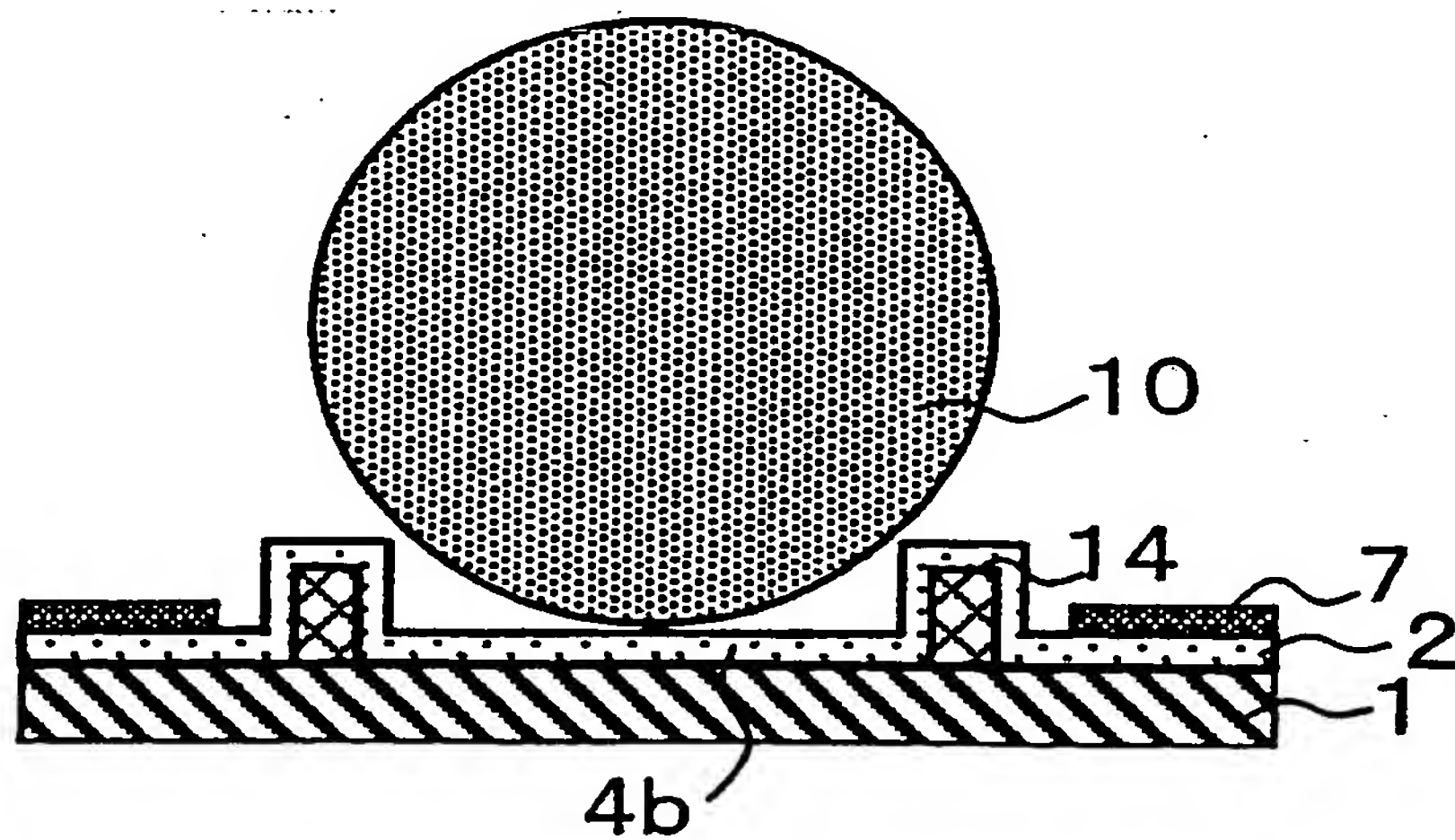
[Fig. 7]



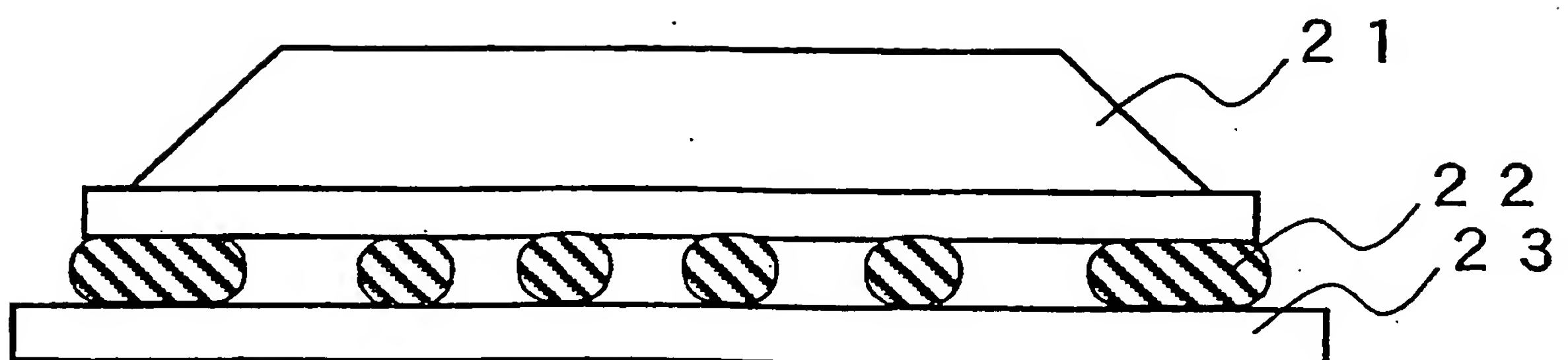
[Fig. 8]



[Fig. 9]



[Fig. 10]



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